MSKSEMI 美森科













ESD

TSS

MOV

GDT

PLED

MMFTN3019E-MS

Product specification





Features

- 30V,200mA, RDS(ON) = $3.5\Omega@VGS = 10V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

Reference News

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
30V	3.5Ω	200mA

Reference News

PACKAGE OUTLINE	PIN Configuration	Marking
SOT-523	G T S	KN

Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V _D s	Drain-Source Voltage	30	V
Vgs	Gate-Source Voltage	±20	V
	Drain Current – Continuous (Ta=25°C)	200	mA
I D	Drain Current – Continuous (Ta=70°C)	150	mA
IDМ	Drain Current – Pulsed¹	0.8	
Б	Power Dissipation (Tc=25°C)	200	mW
PD	Power Dissipation – Derate above 25℃	2.0	mW/℃
Тѕтс	Storage Temperature Range	-55 to 150	$^{\circ}$
TJ	Operating Junction Temperature Range	-55 to 150	$^{\circ}$

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Rеja	Thermal Resistance Junction to ambient		400	°C/W



Electrical Characteristics (T_J=25 °C, unless otherwise noted) Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	30			V
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 25℃ , I _D =1mA		0.05		V/℃
Ipss	Drain-Source Leakage Current	V _{DS} =30V , V _{GS} =0V , T _J =50°C			100	nA
IDSS	Drain-Oddice Leakage Guiterii	VDS=30V , VGS=0V , TJ=75°C			400	nΑ
Igss	Gate-Source Leakage Current	Vgs=±20V , Vps=0V			±6	uA

On Characteristics

R _{DS(ON)} Static Drain-Source On-Resistance	Vgs=10V , Ib=0.2A			3.5	Ω	
1 = =(2.1)	Tabeleny Cambo 215 Country	Vgs=4.5V , ID=0.1A			4.0	
V _{GS} (th)	Gate Threshold Voltage	Vgs=Vps , Ip =250uA	0.8	1.1	1.6	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	,		3		mV/℃

Dynamic and switching Characteristics

	,			
Ciss	Input Capacitance		 23	
Coss	Output Capacitance	V _{DS} =30V , V _{GS} =0V , F=1MHz	 16	 pF
Crss	Reverse Transfer Capacitance		 10	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V , Force Current			200	mA
Isм	Pulsed Source Current	ve ve ev , r eree carrent			400	mA
VsD	Diode Forward Voltage	V _G s=0V , I _S =0.2A , T _J =25°C			1.3	V

Note

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 3. Essentially independent of operating temperature.



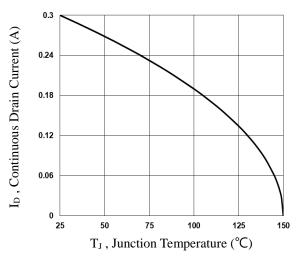


Fig.1 Continuous Drain Current vs. Tc

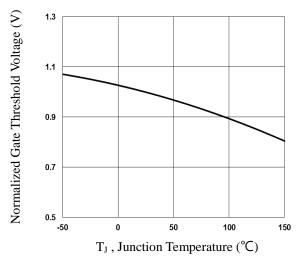


Fig.3 Normalized V_{th} vs. T_J

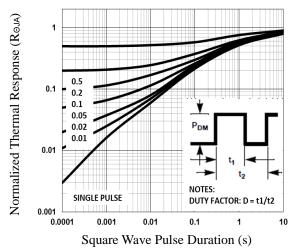


Fig.5 Normalized Transient Response

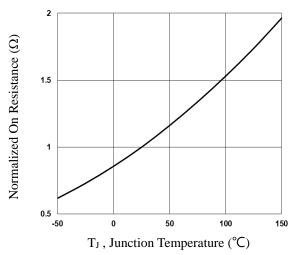
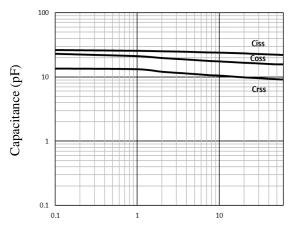


Fig.2 Normalized RDSON vs. TJ



V_{DS}, Drain to Source Voltage

Fig.4 Capacitance Characteristics

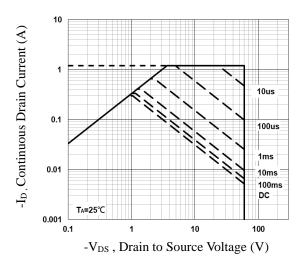
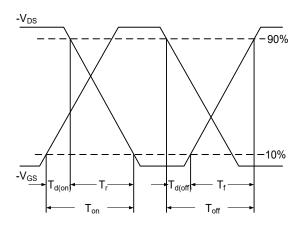


Fig.6 Maximum Safe Operation Area







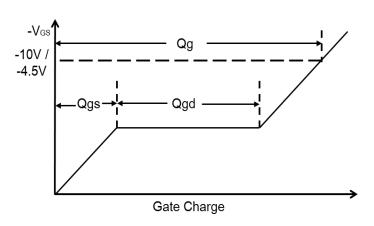
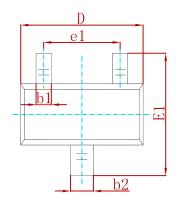
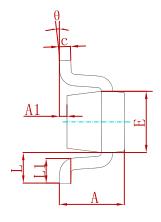


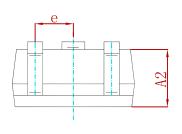
Fig.8 Gate Charge Waveform



PACKAGEMECHANICALDATA

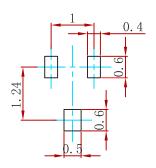






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
А	0.700	0.900	0.028	0.035
A1	0.000	0.100	0.000	0.004
A2	0.700	0.800	0.028	0.031
b1	0.150	0.250	0.006	0.010
b2	0.250	0.350	0.010	0.014
С	0.100	0.200	0.004	0.008
D	1.500	1.700	0.059	0.067
Е	0.700	0.900	0.028	0.035
E1	1.450	1.750	0.057	0.069
е	0.500	TYP.	0.020	TYP.
e1	0.900	1.100	0.035	0.043
L	0.400	REF.	0.016 REF.	
L1	0.260	0.460	0.010	0.018
θ	0°	8°	0°	8°

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
MMFTN3019E-MS	SOT-523	3000



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